



Title of Change:	SuperFET3 Vth test condition update
Effective date:	01 Oct 2020
Contact information:	Contact your local ON Semiconductor Sales Office or Peter.Lee@onsemi.com
Type of notification:	This Product Bulletin is for notification purposes only. ON Semiconductor will proceed with implementation of this change upon publication of this Product Bulletin.
Change Category:	Test Change
Change Sub-Category(s):	Datasheet/Product Doc change

Sites Affected:

ON Semiconductor Sites	External Foundry/Subcon Sites
ON Semiconductor Suzhou, China	None

Description and Purpose:

SuperFET3 Vth test condition update to improve manufacturability for customer support.

Current: Vth test condition($V_{gs}=V_{ds}$, I_d = Rated ID x 1/10,000)

Proposed: Vth test condition($V_{gs}=V_{ds}$, I_d =Active Area x JD value(4.3mA/um²))/Total Affected OPN: 4ea
However the min/max limit will remain as it is.

And the change will not impact form, fit, or function of product(s).

Product	Current Datasheet	New Datasheet condition
NVB110N65S3F	$V_{GS} = V_{DS}$, ID = 3 mA, 3.0 ~ 5.0V	$V_{GS} = V_{DS}$, ID = 0.74 mA, 3.0 ~ 5.0V
NVB082N65S3F	$V_{GS} = V_{DS}$, ID = 4 mA, 3.0 ~ 5.0V	$V_{GS} = V_{DS}$, ID = 1 mA, 3.0 ~ 5.0V
NVHL082N65S3F	$V_{GS} = V_{DS}$, ID = 4 mA, 3.0 ~ 5.0V	$V_{GS} = V_{DS}$, ID = 1 mA, 3.0 ~ 5.0V
NVHL110N65S3F	$V_{GS} = V_{DS}$, ID = 3 mA, 3.0 ~ 5.0V	$V_{GS} = V_{DS}$, ID = 0.74 mA, 3.0 ~ 5.0V

List of Affected Standard Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

NVB110N65S3F	NVB082N65S3F	NVHL082N65S3F
NVHL110N65S3F		